

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
TO, BAN CHIN

Examiner

David J. Makiya

Art Unit

2885

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,763,231 A	08-1988	Houplain, Georges	362/148
*	B	US-5,548,499 A	08-1996	Zadeh, Rohollah E.	362/366
*	C	US-7,217,008 B2	05-2007	Thompson et al.	362/285
*	D	US-2007/0147052 A1	06-2007	Wyatt, Michael Dean	362/365
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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